

Notice of References Cited	Application/Control No. 09/783,707	Applicant(s)/Patent Under Reexamination LENZ ET AL.	
	Examiner Patrick J Assouad	Art Unit 2857	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-2002/0183971 a1	12-2002	Wegerich et al.	702/185
	C	US-2002/0087290 a1	07-2002	Wegerich et al.	702/182
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Chen et al., "SRDE -- Application of Data Similarity to Process Control", 12/1/99.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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